



Wpływ promieniowania na systemy wbudowane

Indeks: **683121** Producent: **Springer** Kod producenta: **9789048174171**

Cena: **493.71 zł**

Opis

Radiation Effects on Embedded Systems

Producent: Springer

- **temat:** Circuits & components, Electrical engineering, Electronics engineering, Medical physics, Nuclear power & engineering, Science / Life Sciences / Biophysics, TECHNOLOGY & ENGINEERING / Electronics / General, TECHNOLOGY & ENGINEERING / Power Resources / Nuclear, Technology & Engineering / Electrical, Technology & Engineering / Electronics / Circuits / General, ANF: Technology, Biochemie, Biophysik, Biologie, Biophysics, Circuits, Circuits & components, Computer engineering, Electrical, Electrical and Electronic Engineering, Electrical engineering, Electronic Circuits and Systems, Electronics, Electronics - Microelectronics, Electronics and Microelectronics, Instrumentation, Electronics engineering, Electronics: circuits and components, Elektronik, Elektronik, Elektrotechnik, Nachrichtentechnik, Elektrotechnik, Engineering, Environmental - General, Environmental Science (see also Chemistry - Environmental), Environmental protection, General, HC, HC/Biologie/Biochemie, Biophysik, HC/Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, HC/Technik/Wärmetechnik, Energietechnik, Kraftwerktechnik, Hardcover, Softcover, Hardcover, Softcover / Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, Kernenergie und Kerntechnik (Nuklearenergie, Nukleartechnik), Life Sciences, Life Sciences - Biophysics, Medical physics, Medizinische Physik, Netherlands, Non-Fiction, Nuclear, Nuclear Energy, Nuclear engineering, Nuclear power & engineering, Nuclear power and engineering, Power Resources, Power Resources - Nuclear, Radiation Dosimetry and Protection, Radiation Effects, Radiation Effects; Radiation ground testing; Signal; analog; circuit; electronics; embedded systems; fault tolerance; integrated circuit; laser; microelectronics; single event effects; single-electron transistor; software; testing, Radiation Effects; Radiation ground testing; Signal; analog; circuit; electronics; embedded systems; fault tolerance; integrated circuit; laser; microelectronics; single event effects; single-electron transistor; software; testing, Radiation ground testing, Radiation ground testing; Signal; analog; Circuit; electronics; Fault Tolerance; integrated circuit; Laser; microelectronics; single event effects; single-electron transistor; Software; testing, SCI/TECH, SCIENCE, SCIENCE / Life Sciences / Biophysics, Schaltkreise und Komponenten (Bauteile), Science/Environmental Science (see also Chemistry - Environmental), Science/Life Sciences - Biophysics, Science/Math, Signal, Systems engineering, TECHNOLOGY & ENGINEERING, TECHNOLOGY & ENGINEERING / Electrical, TECHNOLOGY & ENGINEERING / Electronics / Circuits / General, TECHNOLOGY & ENGINEERING / Electronics / General, TECHNOLOGY & ENGINEERING / Power Resources / Nuclear, Technik, Technology & Engineering/Electrical, Technology & Engineering/Electronics - Microelectronics, Technology & Engineering/Environmental - General, Technology & Engineering/Power Resources - Nuclear, Verstehen, Wärmetechnik, Energietechnik, Kraftwerktechnik, analog, circuit, embedded systems, fault tolerance, integrated circuit, laser, microelectronics, single event effects, single-electron transistor, software, testing, Electronics: circuits and components, Elektronik, Elektrotechnik, Kernenergie und Kerntechnik (Nuklearenergie, Nukleartechnik), Medizinische Physik, Nuclear power and engineering, Schaltkreise und Komponenten (Bauteile), HC/Biologie/Biochemie, Biophysik, HC/Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, HC/Technik/Wärmetechnik, Energietechnik, Kraftwerktechnik
- **wiążący:** paperback
- **język:** english, english, english
- **waga przedmiotu:** 0.87 pounds
- **strony:** 280
- **słowo kluczowe tematu:** Netherlands, Non-Fiction, Radiation Effects, Radiation Effects; Radiation ground testing;

Signal; analog; circuit; electronics; embedded systems; fault tolerance; integrated circuit; laser; microelectronics; single event effects; single-electron transistor; software; testing, Radiation Effects; Radiation ground testing; Signal; analog; circuit; electronics; embedded systems; fault tolerance; integrated circuit; laser; microelectronics; single event effects; single-electron transistor; software; testing, Radiation ground testing, Radiation ground testing; Signal; analog; Circuit; electronics; Fault Tolerance; integrated circuit; Laser; microelectronics; single event effects; single-electron transistor; Software; testing, SCI/TECH, Science/Math, Signal, analog, circuit, electronics, embedded systems

- **marka:** Springer
- **kod unspsc:** 55101500
- **kod podmiotu:** SCI009000, TEC008000, TEC028000, TEC007000, TEC008010, 1675, 1684, 1683, TJFC, TJF, THR, THK, PHVD, THK, TJFC, TJFC, THR, TJF, PHVD, THK
- **grupa docelowa:** College/University
- **numer części:** 9789048174171
- **kolor:** White
- **waga opakowania przedmiotu:** 1 pounds
- **wydanie:** Softcover reprint of hardcover 1st ed. 2007
- **zewnętrznie przypisany identyfikator produktu:** 9048174171, 9789048174171, 09789048174171
- **producent:** Springer
- **gatunek muzyczny:** Circuits & components, Medical physics, Electrical engineering, Electronics engineering, Nuclear power & engineering, TECHNOLOGY & ENGINEERING, Electronics, Circuits, General, SCIENCE, Life Sciences, Biophysics, TECHNOLOGY & ENGINEERING, Electrical, TECHNOLOGY & ENGINEERING, Electronics, General, TECHNOLOGY & ENGINEERING, Power Resources, Nuclear, HC, Technik, Elektronik, Elektrotechnik, Nachrichtentechnik, HC, Biologie, Biochemie, Biophysik, HC, Technik, Wärmetechnik, Energietechnik, Kraftwerktechnik, Electronics: circuits and components, Medical physics, Electrical engineering, Electronics engineering, Nuclear power and engineering
- **Data publikacji:** 2010-10-19T00:00:01Z
- **numer wydania:** 1
- **nazwa przedmiotu:** Radiation Effects on Embedded Systems
- **data premiery:** 2010-10-19T00:00:01Z
- **data uruchomienia strony produktu:** 2010-10-08T01:48:41.809Z

Parametry

Wydanie	I edycja 2007, miękka okładka
Liczba stron	280
Waga	0.87 lbs